Application No.: 09/867,766

IN THE CLAIMS

Please amend the claims as follows:

1. (Currently amended) A semiconductor integrated circuit comprising:

a ROM for storing plural confidential data thereon address by address;

a tester for testing the ROM address by address; and

<u>a storage device means</u> for storing <u>plural</u> redundancy check data <u>address by address</u> that <u>have has been obtained by performing a predetermined calculation on each of the corresponding <u>plural</u> confidential data,</u>

wherein the tester includes a checker for performing <u>substantially</u> the same type of calculation as the predetermined calculation on <u>each of</u> the <u>plural</u> confidential data that has been read out from the ROM address by address, and

wherein a result of the calculation performed by the checker is compared to <u>each of</u> the <u>corresponding plural</u> redundancy check data stored <u>in</u> on the storage <u>device</u> means <u>address by address</u>.

- 2. (Currently amended) The integrated circuit of claim 1, wherein the storage device means is included in the ROM.
- 3. (Currently amended) The integrated circuit of claim 2, wherein the <u>plural</u> redundancy check data and the <u>plural</u> confidential data are stored at mutually different addresses on the ROM.
- 4. (Currently amended) The integrated circuit of claim 2, wherein the <u>plural</u> redundancy check data <u>are stored at certain data bit positions of an address</u>, and

the <u>plural</u> confidential data are stored at <u>remaining data bit positions of</u> the same address on the ROM.

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- 5. (Currently amended) A method of testing a semiconductor integrated circuit including a ROM that stores <u>plural</u> confidential data thereon <u>address by address</u>, the method comprising the steps of:
- a) storing <u>plural</u> redundancy check data, which <u>have</u> has been obtained by performing a predetermined calculation on <u>each of</u> the <u>corresponding plural</u> confidential data, <u>in a on</u> redundancy check data storage <u>device means</u> of the integrated circuit;
- b) reading out <u>each of</u> the <u>plural</u> confidential data from the ROM <u>address by address</u> and performing <u>substantially</u> the same <u>type of</u> calculation as the predetermined calculation on <u>each of</u> the <u>plural</u> confidential data read out; and
- c) reading out <u>each of</u> the <u>corresponding plural</u> redundancy check data from the storage <u>device means address by address</u> and <u>then</u> comparing a result of the calculation performed in the step b) to <u>each of</u> the <u>corresponding plural</u> redundancy check data read out.